9/19/07

Sheet <u>1</u> of <u>1</u>

Substitute Form PTO-1449 (Modified)			Application No. 10/567,883	
1	closure Statement pplicant	Applicant Wilhelm Stein et al.		
(Use several sheets if necessary) (37 CFR \$1.98(b))		Filing Date August 14, 2006	Group Art Unit 2811	

			U.S. Patent	Documents			
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	•					
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

	Foreig	n Patent Doc	uments or Pu	blished Foreign	Patent A	Application	าร	
Examiner	Desig.	Document	Publication	Country or				lation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
/FYL/	AL	WO 01/41225	6/7/2001	WIPO				
	AM							
•	AN							
	AO							
 	AP							

	Other Documents (include Author, Title, Date, and Place of Publication)							
Examiner Initial	Desig. ID	Document						
	AQ							
	AR							
	AS							
	AT							

Examiner Signature /Feifei Yeung Lopez/ (12/10/2007)	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if no	t in conformance and not considered. Include copy of this form with

next communication to applicant.

IAP5 Rec'd PCT/PTO 0.9 FEB 2006 of

Substitute Form PTO-1449 (Modified)

U.S. Department of Commerce Patent and Trademark Office

Attomey's Docket No. 12406-147US1

Application No. To Be Assigned

Information Disclosure Statement by Applicant (Use several sheets if necessary)

Applicant Wilhelm Stein et al.

Filing Date Herewith Group Art Unit

(37 CFR §1.98(b))

			_	U.S. Pate	ent Documents			
	aminer Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
/F	YL/	AA	5,115,286	05/19/1992	Camras et al.			
		AB	5,889,295	03/30/1999	Rennie et al.			
		AC	5,861,636	01/19/1999	Dutta et al.			
		AD	6,403,987	06/11/2002	Miki et al.			
		AE	2002/0074558	06/20/2002	Hata et al.			
		AF	6,420,732	07/16/2002	Kung et al.		:	
		AG	2002/0096687	07/25/2002	Kuo et al.			
		AH	2002/0137244	09/26/2002	Chen et al.			
		AI	6,878,563	04/12/2005	Bader et al.			
		AJ						
	, .	AK						

Foreign Patent Documents or Published Foreign Patent Applications									
Examiner		Desig.	Document	Publication	Country or			Translation	
İ	nitial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
/F`	YL/	AL	DE 19820777	11/12/1998	Germany			Equivalent to US 6,403,987	
		AM	DE 10020464	11/08/2001	Germany			Equivalent to US 6,878,563	
		AN	EP 1 271665	01/02/2003	Europe			-	
1	/	AO	JP 2000- 353820	12/19/2000	Japan			Abstract	
		AP							

	Other Documents (include Author, Title, Date, and Place of Publication)							
Examiner	Desig.							
Initial	ID_	<u>Document</u>						
	AQ							
	AR							
	AS							
	AT							

	<u> </u>
Examiner Signature	Date Considered
/Feifei Yeung Lopez/ (12/10/2007)	
EXAMINER: Initials citation considered Draw line through citation if no	t in conformance and not considered. Include conv of this form with

next communication to applicant.